INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)

Docket Number (Optional)	Application Number				
TWI-30730	NEW 10/796 322				
Applicant(s)					
Adam Norton et al.					
Filing Date	Group Art Unit				
HEREWITH	Unknown 2877				

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	Name	CLASS	SUBCLASS	FILING DATE
al	*AA	4,776,695	10/11/1988	van Pham et al.	356	328	09/02/1986
Al	*AB	5,659,397	08/19/1997	Miller et al.	356	446	06/08/1995
RE	*AC	5,747,813	05/05/1998	Norton et al.	250	372	04/14/1994
48	*AD	US 2002/0021441	02/21/2002	Norton et al.	356	326	08/17/2001

FOREIGN PATENT DOCUMENTS

		DOCUMENT					· Tr	ANSLATION
_	REF	NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	No
al	*AE	57-106846	07/02/1982	Japan (w/English abstract)	G01N	21/62	X	
de	*AF	WO 00/57127	09/28/2000	PCT	G01B	11/06		

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

W	*AG	K. Goto et al., "On-line System for Measuring Thickness of Hydrated Chromium Oxide Film on Tin Free Steel," Iron and Steel, Issue 9, 1984, pp. 1088-1094. (includes translation)
Ka	*AH	G. Harbeke et al., "Rapid Characterization of Polysilicon Films by Means of a UV Reflectometer," RCA Review, Vol. 44, March 1983, pp. 19-29.

Examiner	Date Considered 8 - 2004					
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if						
not in conformance and not considered. Include copy of this form with next communication to applicant.						